

# 제20회 한국반도체학술대회

2013년 2월 4일(월)~6일(수) / 웰리힐리파크 (구, 성우리조트)

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## G. Device & Process Modeling, Simulation and Reliability 분과

Room H

난실 (본관, 5층)

2013년 2월 6일(수) 12:45-14:00

[WH2-G] Device Characterization

좌장: 이성현(한국외국어대학교), 이재규(삼성전자)

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- WH2-G-1    12:45-13:00    **Random Telegraph Noise Generated in the Space Region between Adjacent Word-Lines in 26nm NAND Flash Memory**  
Ho-Jung Kang<sup>1</sup>, Sung-Min Joe<sup>1</sup>, Min-kyu Jeong<sup>1</sup>, Kyoung-Rok Han<sup>2</sup>, Sung-Kye Park<sup>2</sup>, and Jong-Ho Lee<sup>1</sup>  
<sup>1</sup>Department of EECS and ISRC, Seoul National University, <sup>2</sup>R&D Division, SK Hynix Inc.
- WH2-G-2    13:00-13:15    **Characterization of Low Frequency Noise in PtSi Source/Drain Schottky Barrier Junction SOI MOSFETs**  
Jong-Ho Bae<sup>1</sup>, MoonGyu Jang<sup>2</sup>, Chan Hyeong Park<sup>3</sup>, Byung-Gook Park<sup>1</sup>, and Jong-Ho Lee<sup>1</sup>  
<sup>1</sup>School of EECS and ISRC, Seoul National University, <sup>2</sup>Electronics and Telecommunications Research Institute, <sup>3</sup>Department of ECE, Kwangwoon University
- WH2-G-3    13:15-13:30    **Monochromatic Photonic Capacitance-Voltage Technique for Donor- and Acceptor-Like Density-of-States over the Full-Energy Range in Amorphous TFTs**  
Hagyoul Bae<sup>1</sup>, Hyunjun Choi<sup>1</sup>, Sungwoo Jun<sup>1</sup>, Chunhyung Jo<sup>1</sup>, Yun Hyeok Kim<sup>1</sup>, Jaewook Lee<sup>1</sup>, Seonwook Hwang<sup>1</sup>, Euiyeon Hong<sup>1</sup>, Inseok Hur<sup>1</sup>, Jun Seok Hwang<sup>1</sup>, Jaeyeop Ahn<sup>1</sup>, Dae Geun Kim<sup>1</sup>, Bong Sik Choi<sup>1</sup>, Saeroonter Oh<sup>2</sup>, Dae-Hawn Kim<sup>2</sup>, Jonguk Bae<sup>2</sup>, and Dong Myong Kim<sup>1</sup>  
<sup>1</sup>School of Electrical Engineering, Kookmin University, <sup>2</sup>Research and Development Center, LG Display
- WH2-G-4    13:30-13:45    **Characterization of Free Electron-Deembedded Subgap Density-of-States in A-IGZO TFTs from the Sub-Bandgap Optical Subthreshold Characteristics**  
Hyojoon Seo, Hagyoul Bae, Chunhyung Jo, Euiyeon Hong, Hyunjun Choi, Jun Seok Hwang, Jaeyeop Ahn, Dae Hwan Kim, and Dong Myong Kim  
School of Electrical Engineering, Kookmin University

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WH2-G-5      13:45-14:00      **Photonic Capacitance-Voltage Technique for Intrinsic Subgap-DOS Considering the Parasitic Capacitance in Amorphous Oxide Semiconductors**

Hagyoul Bae<sup>1</sup>, Hyunjun Choi<sup>1</sup>, Sungwoo Jun<sup>1</sup>, Chunhyung Jo<sup>1</sup>, Yun Hyeok Kim<sup>1</sup>, Jaewook Lee<sup>1</sup>, Seonwook Hwang<sup>1</sup>, Euiyeon Hong<sup>1</sup>, Inseok Hur<sup>1</sup>, Dong Jae Shin<sup>1</sup>, Kyung Min Lee<sup>1</sup>, Hyeongjung Kim<sup>1</sup>, Saeroonter Oh<sup>2</sup>, Dae-Hawn Kim<sup>2</sup>, Jonguk Bae<sup>2</sup>, and Dong Myong Kim<sup>1</sup>

<sup>1</sup>School of Electrical Engineering, Kookmin University, <sup>2</sup>Research and Development Center, LG Display